FORM PTO-1449 (REV. 7-85)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

ATTY. DOCKET NO. 50081USNP APPLICATI N NO. 10/055,109 APPLICANT Shi ET AL.

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U.S. PATENT DOCUMENTS										
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent pages, Etc.)										
		AT	Vos P., et al. "AFLP: A new technique for DNA fingerprinting", Nucleic Acids Research 23 (21):4407-4414 (1995).							
	_	AU	Wurff Van Der AWG, et al., "TE-AFLP: Combining rapidity and robustness in DNA fingerprinting". Nucleic Acids Research 28 (24):e105 (1-5) (2000).							
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11		Li, Bu-yu et al. "Analysis of Differential Gene expression by ligation specificity-based transcript profiling", OMICS A Journal of Integrative Biology 6 (2):175-185 (2002).								
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